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INFORMATION DISCLOSURE CITATION IN AN APPLICATION		APPLICANT Meral Bradley Woodberry				
		FILING DATE: March 15, 2000		GROUP ART UNIT		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	DATE IF APPROP.
VN	5,047,711	09/10/91	Smith et al.	324	158R	08/23/89
VN	4,968,931	11/06/90	Littlebury et al.	324	158R	11/03/89
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY/NAME	CLASS	SUB CLASS	TRANSLATION YES NO
OTHER DOCUMENTS						
VN	Article entitled, "Securing Known Good Die", by T. A. Williams, published in Advanced Packaging, Fall 1992, pp. 50-59					
VN	Article entitled, Known-Good Die Poised to Take Off", by D. Maliniak, published in Electronic Design, 11-21-94, pp. 55-73					
VN	Article entitled, "Burn-In Co-Developed by TI, MicroModule System, Intel Launches 'SmartDie' Program, by Jim Detar, published in Electronic News, May 30, 1994					
VN	Article entitled, "Known Good Die: A Commercial Solution for Burn-in and Test Before Packaging" by S-H Foo and L. Prokopchak, presented at Semicon Japan, 12-94					
VN	Article entitled, "Flexibility and Modularity Drive Today's Burn-In/Test Systems" by P. Mayerfeld, reprinted from EE-Evaluation Engineering, November 1994					
VN	Specification entitled, "Known Good Die - The Total Solution", AEHR Test Systems/Nitto-Denko					
EXAMINER Ninh Nguyen			DATE CONSIDERED 10/09/03			